

# POLARIZATION-INDEPENDENT REFLECTOMETRY, AND POLARIZATION-INDEPENDENT REFLECTOMETER

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## Abstract of JP2000097856

**PROBLEM TO BE SOLVED:** To measure a reflectance distribution for a measured optical circuit without regulating a polarization condition in local light emission.

**SOLUTION:** When light emitted from a light source 1 is branched by an optical fiber coupler 2 to make one of the branched lights incident into measured light module 3 as measured light, and when the other is associated with reflected light from the module 3 by an optical fiber coupler 21 to interfere with it after group delay is imparted to the other as local emitted light by an optical fiber delay line 5, a reflector 25 or the like, beat signals are generated with respective polarization rotational angles using a polarization rotation angle optical module 100 comprising a polarizer and a polarization rotating device for rotating optionally a polarized condition from 0 deg. to 90 deg., and intensities of them are summed up to measure reflected light power irrespective of the polarized conditions of the local emitted light and reflected light.

